



# Test Report

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RALEC ELECTRONIC CORPORATION  
NO. 1, CENTRAL 2ND STREET, NANTZE EXPORT PROCESSING ZONE,  
KAOHSIUNG, TAIWAN




The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description	:	LEAD FREE CHIP RESISTOR PRODUCT
Style/Item No.	:	RTT05(0805T)RTT05J101
Sample Receiving Date	:	2007/06/11
Testing Period	:	2007/06/11 TO 2007/6/20

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<b>Test Requested</b>	:	In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.
<b>Test Method</b>	:	(1) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.
<b>Test Result(s)</b>	:	Please refer to next page(s).

  
**Katherine Ho / Supervisor**  
**Signed for and on behalf of**  
**SGS Taiwan Limited**

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